

Device and method for removing tested semiconductor components

Abstract

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The invention is based on a device for removing tested semiconductor components from a clamping carrier having fixed stop elements and movable clamping elements, pre-tensioned by spring elements. According to the invention the device has the following features:

- 10 • an actuation device arranged above the clamping carrier, which moves the clamping elements into an opening position enabling the clamping carrier to be discharged, and then moves the clamping elements into a rest position after discharge,
- 15 • an intermediate carrier, positioned under the clamping carrier during discharge, onto which the clamping carrier is emptied,
- a data memory in which data about each semiconductor component are stored, and
- 20 • a removal device, which removes the semiconductor components from the intermediate carrier and sorts them into at least two different categories in accordance with the data stored in the data memory.

Fig. 4